Characterization of Minerals, Metals, and Materials

This symposium will focus on the characterization of the minerals, metals, and materials and the applications of characterization results on the processing of these materials. Subjects include extraction and processing of various minerals; metals (including ferrous, non-ferrous, and precious metals and alloys); metal-matrix composites; glass; ceramic and refractories; polymers; fiber materials; biomaterials; carbon; electronic, magnetic and optical materials; high-temperature materials; newly developed advanced materials; gaseous, liquid, and solid pollutants; recycling; insulation materials; and advanced characterization techniques.

Areas of interest include:

- Techniques for characterizing materials across a spectrum of systems and processes
- Characterization of mechanical, electrical, electronic, optical, dielectric, magnetic, physical, and chemical properties of materials
- Characterization of processing of materials
- Characterization of structural, morphological, and topographical properties of materials
- Emerging characterization techniques
- Characterization of extraction and processing, which include process development and analysis of various processes
- Characterization of microstructure and properties of materials, which include: process integration, characterization of thin and thick films (semi-conductor), micro-texture, computer tomography (CT), x-ray tomography (XRT), in-situ microscopy, nano-scale TEM, AFM, FIB techniques, and GeoMet

Organizers include:
Shadia Ikhmayies, Al Isra University (Jordan)
Bowen Li, Michigan Technological University (USA)
John Carpenter, Los Alamos National Laboratory (USA)
Jiann-Yang Hwang, Michigan Technological University (USA)
Sergio Monteiro, Military Institute of Engineering, IME, Materials Science Department (Brazil)
and others

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